

Exams for group M17-406

Mon, 18 Dec	20:25 — 22:00	TEST	English Language (Technological Terminology) ♣ 325
Fri, 22 Dec	20:25 — 22:00	ATT	Nuclear Physics ♣ Garmash A.A. ♣ dep.27
Sat, 23 Dec	12:00 — 15:00	TEST	Academic (Research) Practice ♣ Barbashov V.M., Krasnyuk A.A. ♣ dep.3
Mon, 25 Dec	18:45 — 20:20	TEST	Selected Chapters of Higher Mathematics ♣ Barbashov V.M., Trushkin N.S. ♣ D-314
Tue, 26 Dec	18:45 — 20:20	TEST Elect	High-Performance Computing Systems ♣ Krasnyuk A.A., Bobkov S.G. ♣ FGU FNTS NIISI RAN
Tue, 26 Dec	18:45 — 20:20	TEST Elect	Interaction of RF Electromagnetic Radiation with Semiconductor Electronics Materials (Physics Principals) ♣ Shurenkov V.V. ♣ V-119
Wed, 27 Dec	18:45 — 20:20	ATT Elect	Microsystems ♣ Boychenko D.V., Demidova A.V. ♣ D-418
Wed, 27 Dec	18:45 — 20:20	ATT Elect	Optoelectronic Devices and Systems ♣ Voronov Y.A. ♣ D-302
Thu, 28 Dec	17:55 — 19:30	ATT Elect	Materials Science ♣ Krasnyuk A.A. ♣ V-315
Thu, 28 Dec	17:55 — 19:30	ATT Elect	Microelectronic Sensors and Transducers ♣ Podlepetskiy B.I. ♣ D-302
Thu, 28 Dec	19:35 — 21:10	ATT Elect	Integrated Microwave Systems ♣ Chukov G.V., Elesin V.V. ♣ V-417
Thu, 28 Dec	19:35 — 21:10	ATT Elect	Electromagnetic Compatibility (Emc) ♣ Shurenkov V.V. ♣ V-119
Tue, 09 Jan	09:00 — 13:00	EXAM Elect	Integrated Microwave Systems ♣ Elesin V.V., Chukov G.V. ♣ V-409
Tue, 09 Jan	09:00 — 13:00	EXAM Elect	Electromagnetic Compatibility (Emc) ♣ Shurenkov V.V. ♣ V-119
Sat, 13 Jan	09:00 — 13:00	EXAM	Nuclear Physics ♣ Garmash A.A. ♣ V-409
Thu, 18 Jan	09:00 — 13:00	EXAM Elect	Materials Science ♣ Krasnyuk A.A. ♣ V-418
Thu, 18 Jan	09:00 — 13:00	EXAM Elect	Microelectronic Sensors and Transducers ♣ Podlepetskiy B.I. ♣ D-302
Mon, 22 Jan	09:00 — 13:00	EXAM Elect	Microsystems ♣ Boychenko D.V., Demidova A.V. ♣ V-315
Mon, 22 Jan	09:00 — 13:00	EXAM Elect	Optoelectronic Devices and Systems ♣ Voronov Y.A. ♣ D-303